FOX-1P™
FULL WAFER CONTACT

Full Wafer Test System

Single Touchdown High Volume Production Test Solution

* Shown with a dual chuck prober, dual FOUP loader and two independent FOX-1P test systems

SYSTEM BENEFITS

- Enables High Throughput, Single Touchdown, Full Wafer Production Testing
  - Capable of simultaneously testing up to 16,000 die in a single wafer touchdown
  - Resource configurable up to 16,384 "Universal Channels" - each programmable as an I/O, Clock, Pin Parametric Measurement Unit (PPMU) or Device Power Supply (DPS)
  - Software-enabled per site flexibility to support small and large device pin count test needs
- Comprehensive functional and parametric test capabilities
  - Deep functional pattern data and capture memory optimized for BIST/DFT testing
  - Per channel PMU for per site parametric testing
  - Individual channel over-current protection to protect wafers and probe cards
- Configured for high volume production
  - Compatible with industry standard probers and probe cards
  - Available as an integrated test cell with prober, probe cards and 16,384 channel probe I/F
  - Configurable as a single or dual system integrated test cell

"Changing the Way ICs Are Tested"

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AEHR TEST SYSTEMS